



Chip-Scale Energy and Power... and Heat

Dr. Thomas Kenny

Program Manager,
DARPA's Microsystems
Technology Office

The views and opinions presented by the invited speakers are their own and should not be interpreted as representing the official views of DARPA or DoD

Approved For Public Release, Distribution Unlimited

Report Documentation Page

Form Approved
OMB No. 0704-0188

Public reporting burden for the collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to a penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number.

| | | | | | |
|--|---------------------|---------------------|-----------------------------|---|---------------------------------|
| 1. REPORT DATE 04 MAR 2009 | | 2. REPORT TYPE | | 3. DATES COVERED 00-00-2009 to 00-00-2009 | |
| 4. TITLE AND SUBTITLE Getting the Heat Out | | | | 5a. CONTRACT NUMBER | |
| | | | | 5b. GRANT NUMBER | |
| | | | | 5c. PROGRAM ELEMENT NUMBER | |
| 6. AUTHOR(S) | | | | 5d. PROJECT NUMBER | |
| | | | | 5e. TASK NUMBER | |
| | | | | 5f. WORK UNIT NUMBER | |
| 7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Defense Advanced Research Projects Agency, Microsystems Technology Office (MTO), 3701 North Fairfax Drive, Arlington, VA, 22203 | | | | 8. PERFORMING ORGANIZATION REPORT NUMBER | |
| 9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES) | | | | 10. SPONSOR/MONITOR'S ACRONYM(S) | |
| | | | | 11. SPONSOR/MONITOR'S REPORT NUMBER(S) | |
| 12. DISTRIBUTION/AVAILABILITY STATEMENT Approved for public release; distribution unlimited | | | | | |
| 13. SUPPLEMENTARY NOTES MTO (DARPA Microsystems Technology Office) Symposium, 2009, Mar 2-5, San Jose, CA | | | | | |
| 14. ABSTRACT | | | | | |
| 15. SUBJECT TERMS | | | | | |
| 16. SECURITY CLASSIFICATION OF: | | | 17. LIMITATION OF ABSTRACT | 18. NUMBER OF PAGES | 19a. NAME OF RESPONSIBLE PERSON |
| a. REPORT | b. ABSTRACT | c. THIS PAGE | | | |
| unclassified | unclassified | unclassified | Same as Report (SAR) | 28 | |

Getting the Heat Out

Dr. Thomas Kenny
DARPA/MTO
March 4, 2009



MICROSYSTEMS TECHNOLOGY OFFICE

Approved For Public Release, Distribution Unlimited



Exciting Technologies



Exciting Technologies

Packed into Tiny Systems



Exciting Technologies

Packed into Tiny Systems

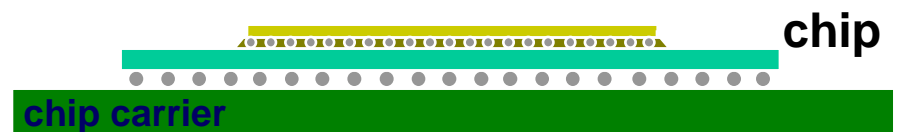
Generating a lot of Heat!



Microelectronics Packaging Today



- **Best modern technology in the electronics layer**





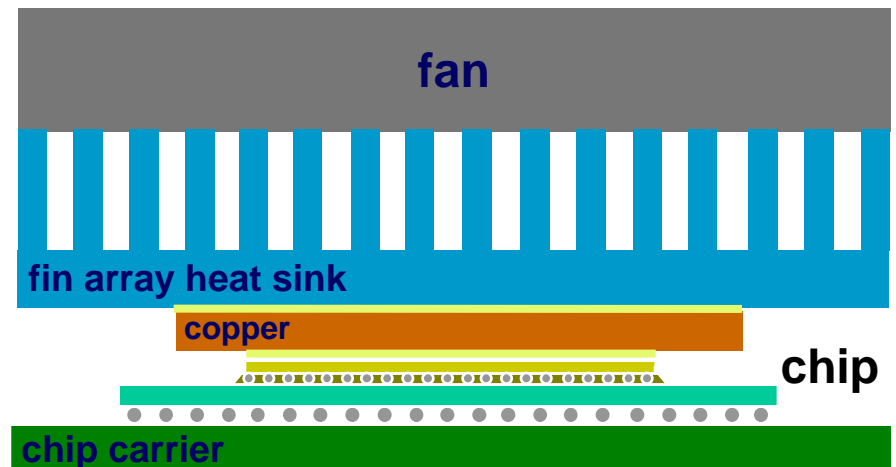
Microelectronics Packaging Today



- Best modern technology in the electronics layer

Ancient “technology” in the thermal layer

(side view)





Microelectronics Packaging Today



The growing size of the thermal solution is a source of :

- **Mechanical failure problems**
- **Weight problems**
- **System size for multi-processor systems (servers)**
- **Significant added cost**
- **Reliability problems (fan)**
- **Crowding away the power conditioning elements**

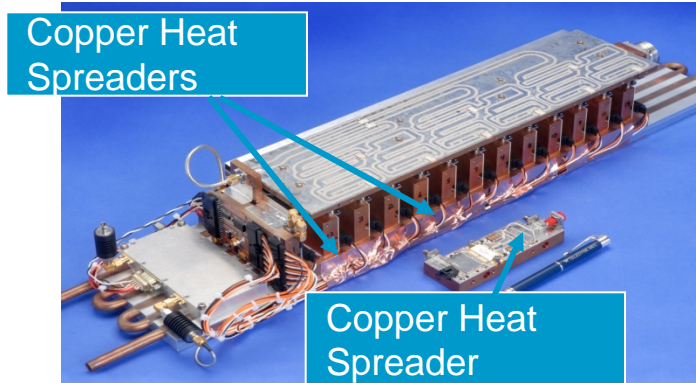
**Things are bad in the commercial sector,
and MUCH WORSE in the DoD...**



Examples of DoD Systems Constrained by Thermal Management

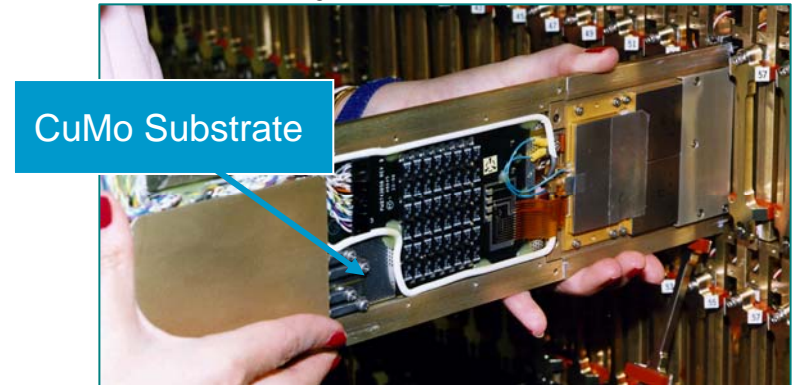


Teledyne's ALQ-99 TWT Replacement Module



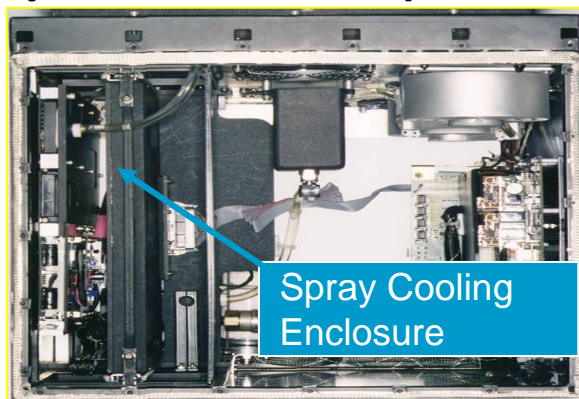
Solid Copper Spreaders used on High-G Platforms add Significant Weight to Avionics

Raytheon's High Power Density Phased Arrays



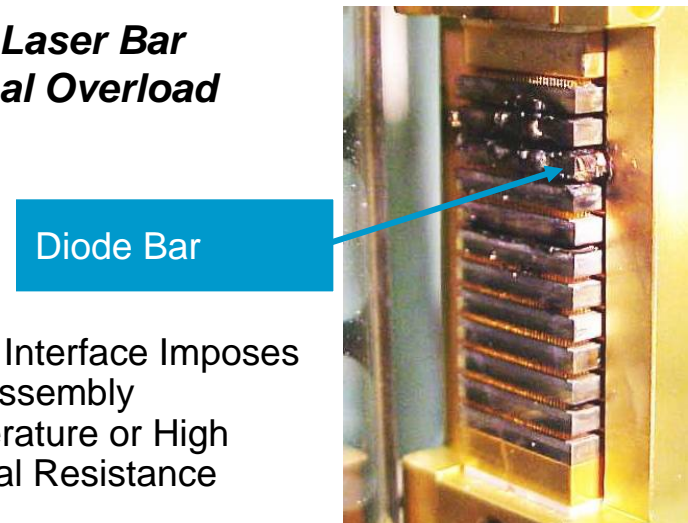
CuMo MCM Substrates Prevent Further Power Scaling in Array Radar Systems

Cray J90 Airborne Computer



Large, Heavy, Complex Facilities for Spray Cooling

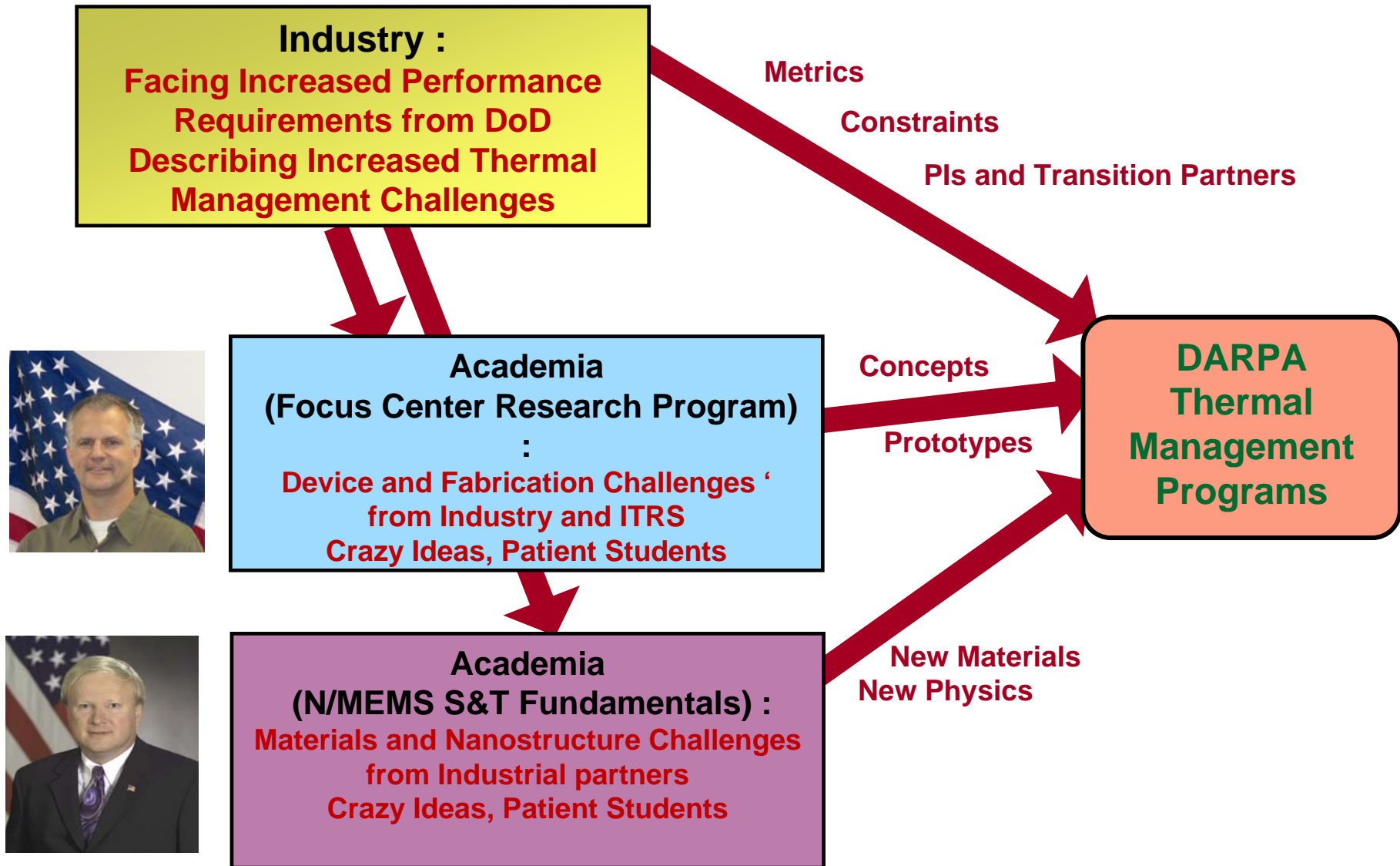
Diode Laser Bar Thermal Overload



Solder Interface Imposes High Assembly Temperature or High Thermal Resistance

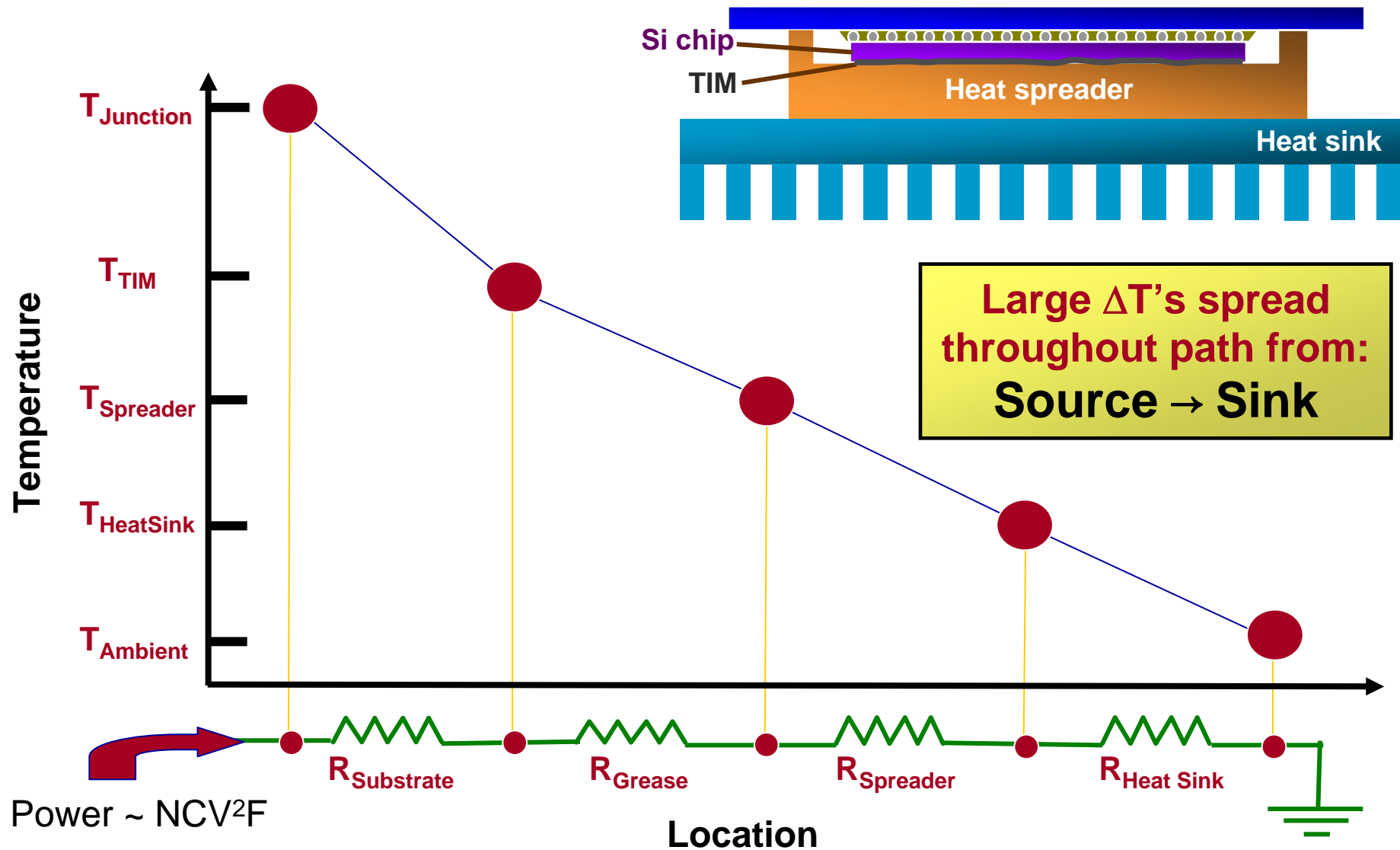


DARPA Approach to Thermal Management Challenges



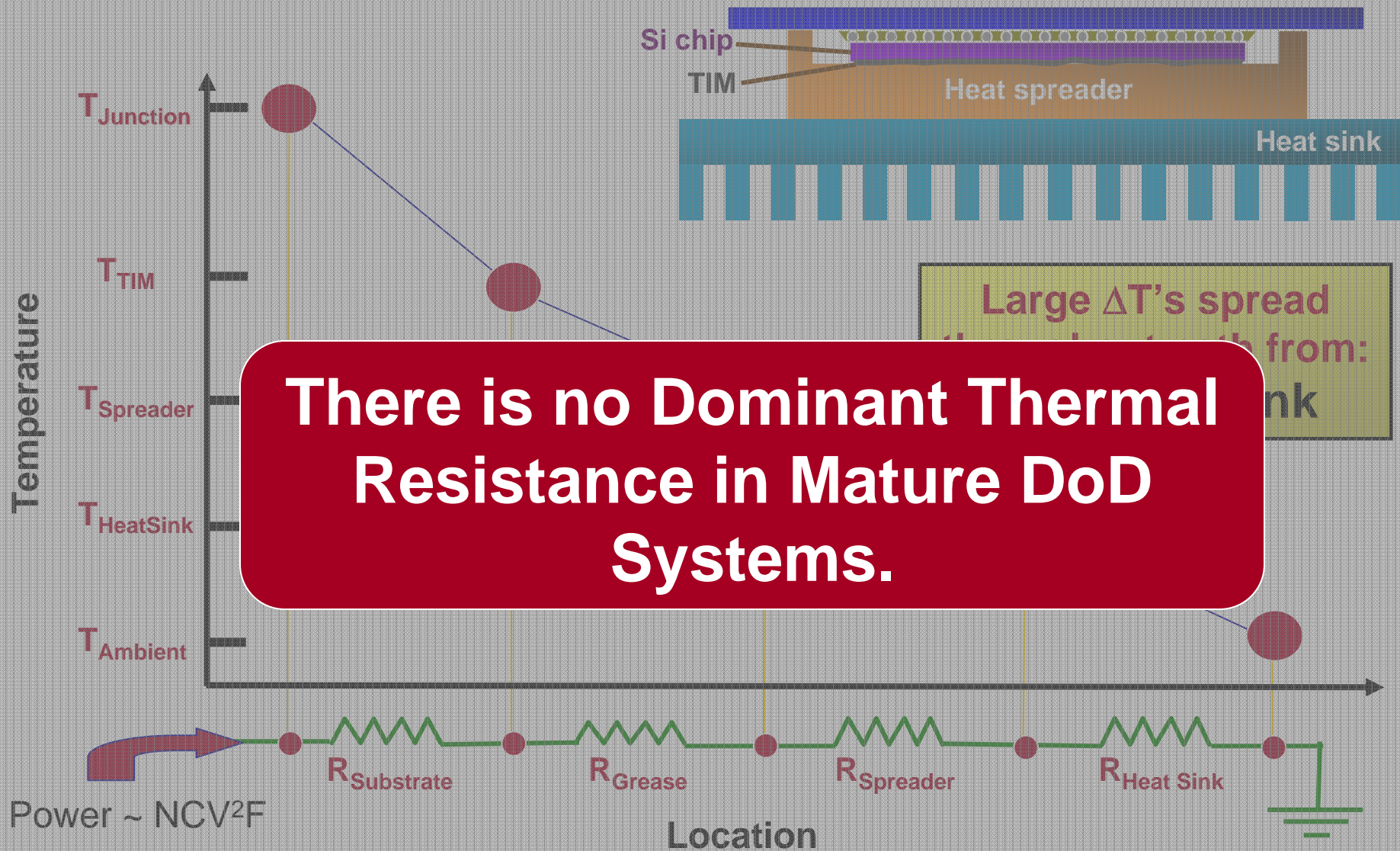


Thermal Resistance Breakdown Where is the Problem?



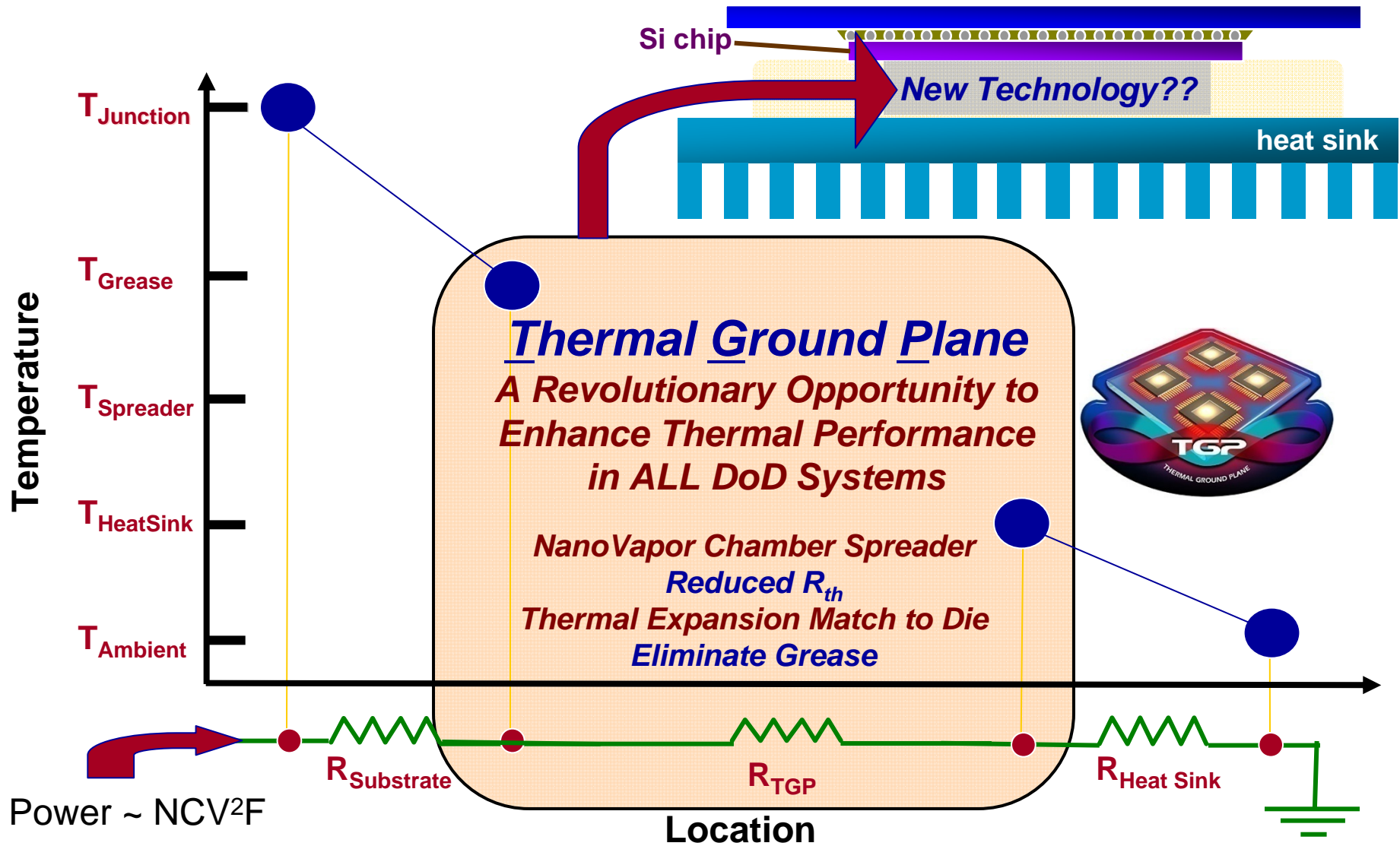


Thermal Resistance Breakdown Where is the Problem?





Thermal Ground Plane (TGP)

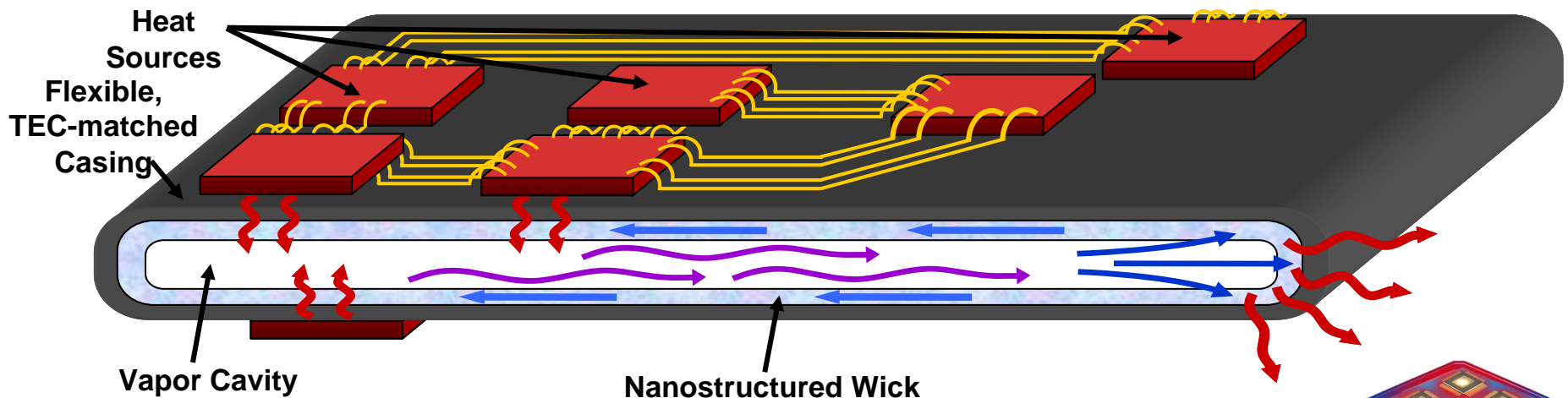




Thermal Ground Plane (TGP)



TGP Program Vision: A new 2-D, thin, lightweight MCM substrate incorporating modern and nanostructured materials to achieve vastly superior thermal conduction & possessing all mechanical properties necessary for hard-mounting ICs.

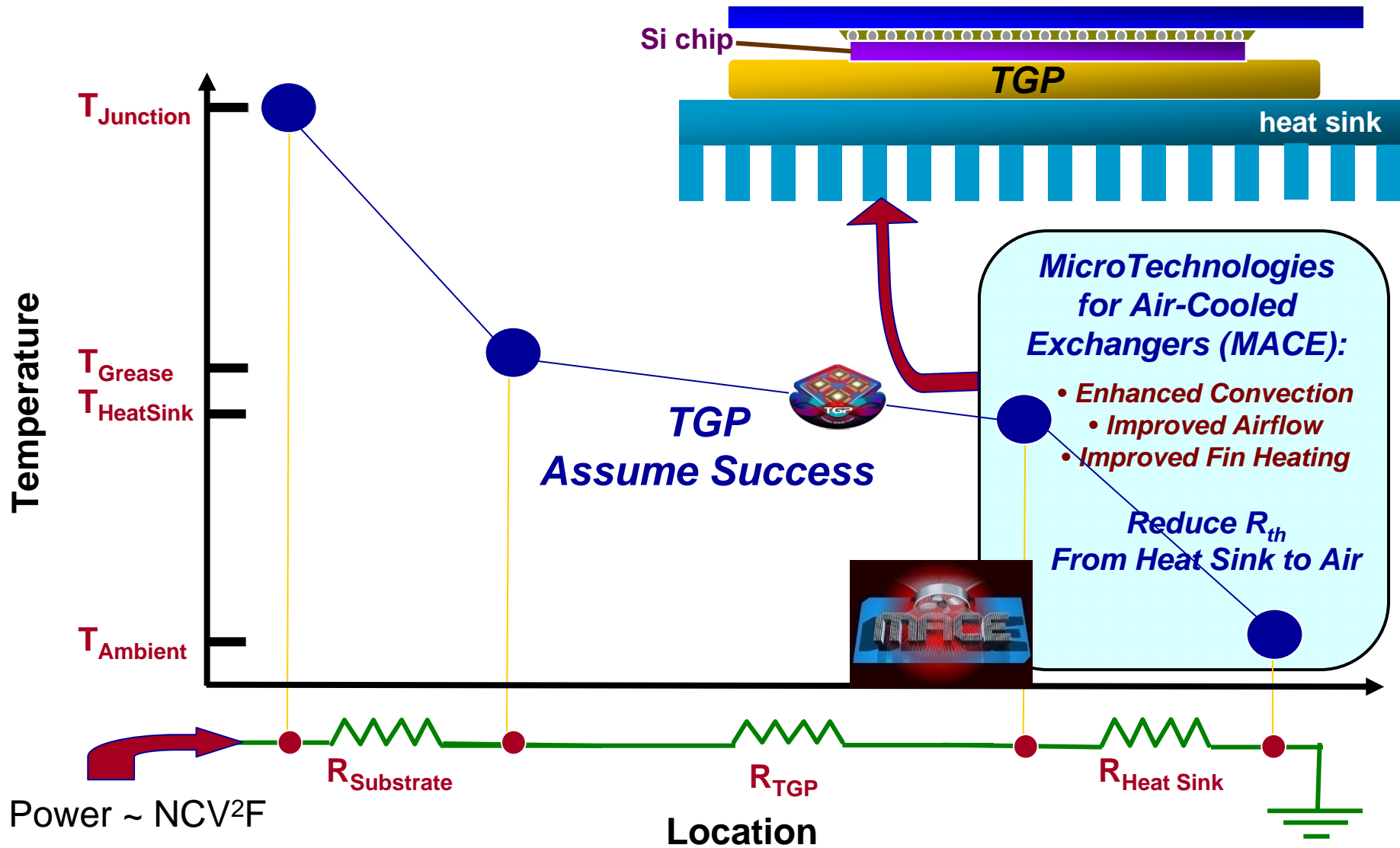


- Extreme lateral thermal conduction, 100X above current MCM substrates
- Large 2-D area, <1 mm thick, Operation up to 20g
- Nanostructured wick for enhanced heat transfer and fluid transport
- Structural, flexible, thin, & light-weight materials that match the TEC of Si, GaAs, or GaN
- 2-phase heat transfer to eliminate load-driven thermal non-uniformity across substrate

Program Kickoff 1/08



A New Thermal Opportunity

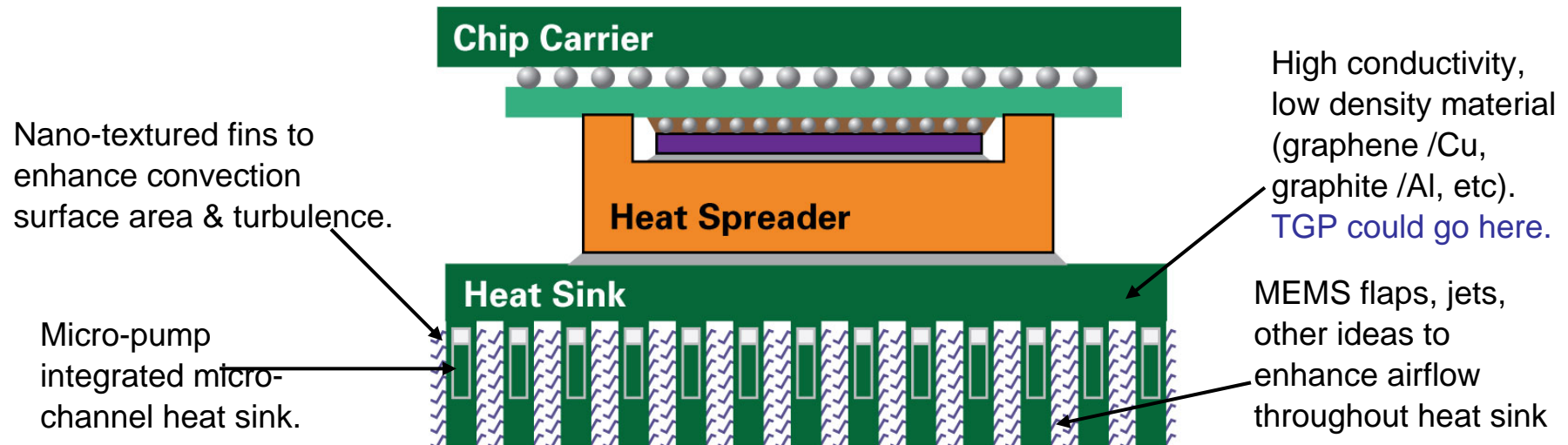




Microtechnologies for Air Cooled Exchangers (MACE)



MACE Program Vision : Develop new technologies to enhance the performance of heat sinks by reducing thermal resistance and airflow resistance. MACE will enable lighter, more compact systems with better thermal performance. MACE complements the Thermal Ground Plane (TGP) program.



MACE Goals:

- Reduction in Thermal Resistance from Heat Sink to Air
- Reduction in Airflow Resistance through Heat Sink
- Use of Direct Air Cooling in Dense High-Power Systems
- Reduced Power Consumption in Cooling Systems



Program Kickoff 1/09.

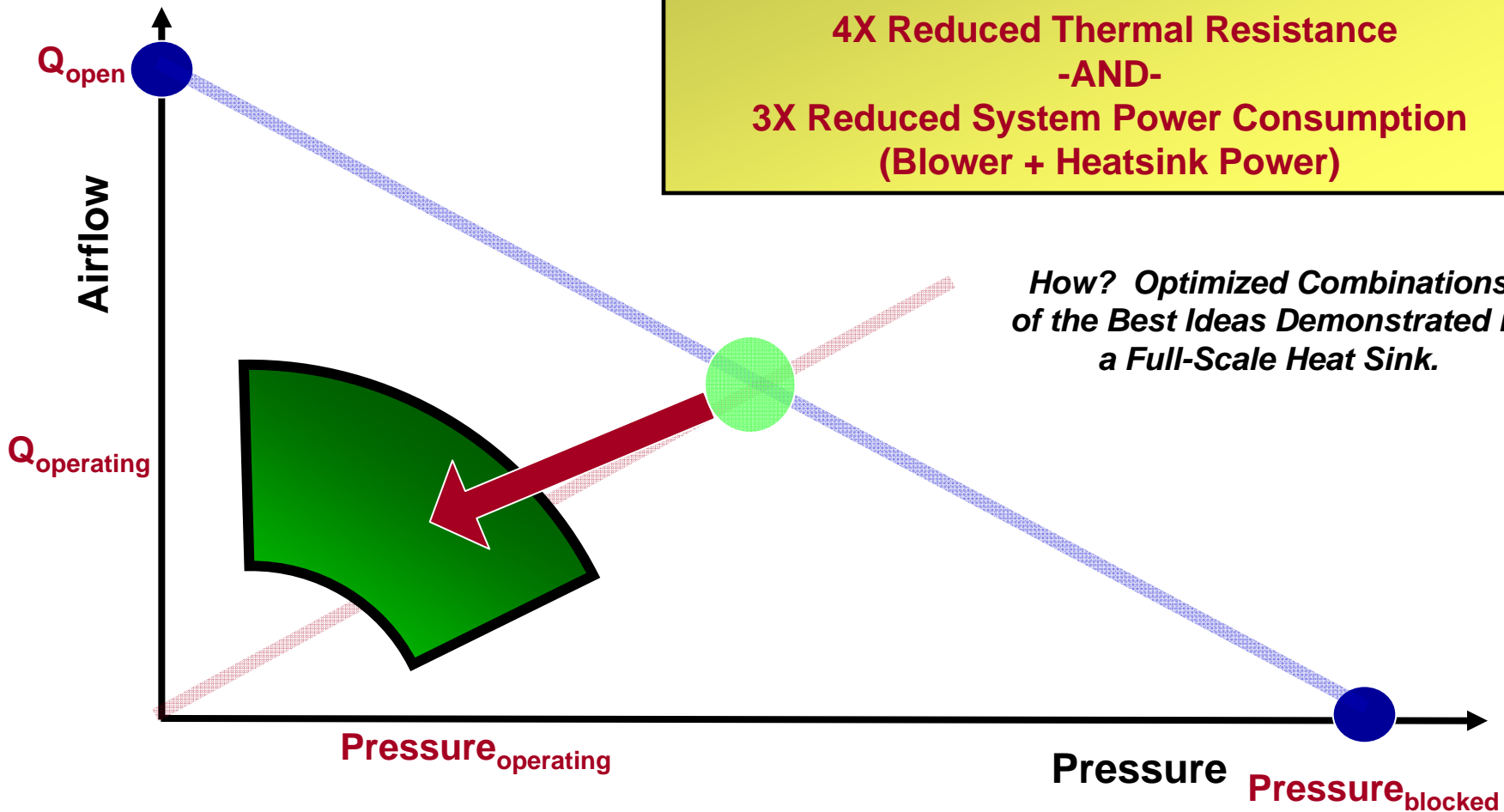


MACE Program Goals



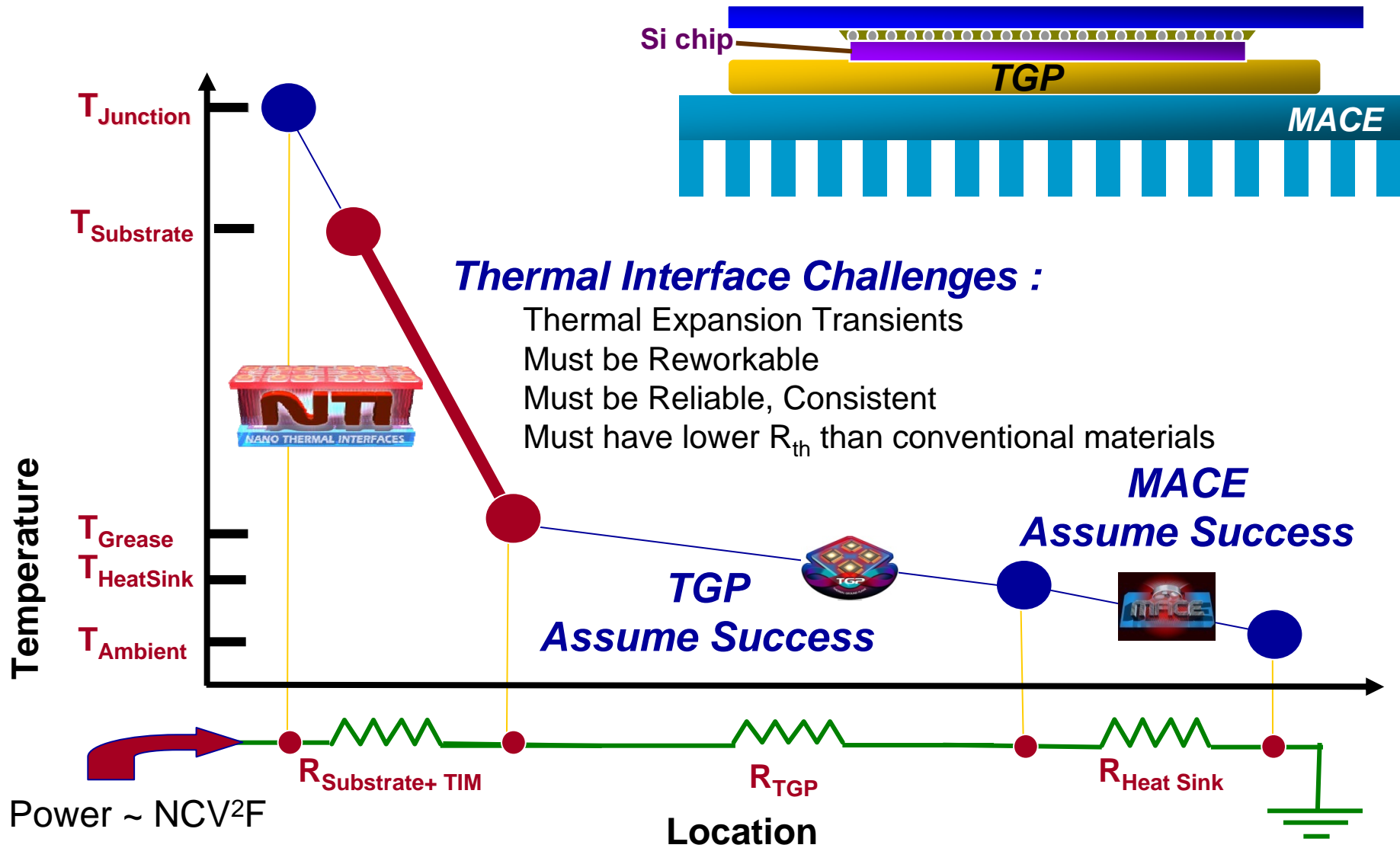
MACE Goals :
**Enable New System Operating Points
At Better Performance and Lower Power**

**4X Reduced Thermal Resistance
-AND-
3X Reduced System Power Consumption
(Blower + Heatsink Power)**





The Next Thermal Opportunity





NanoThermal Interfaces (NTI)



Thermal Interface materials (TIM):

Resistance of thermal interface materials – emerging bottleneck in thermal management of all DoD systems.

Success in TGP and MACE will shift focus to this layer.

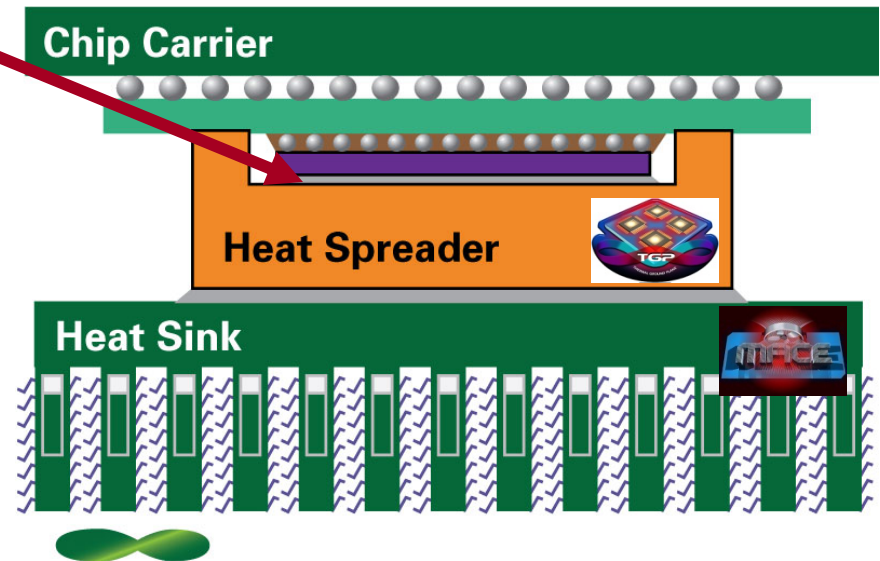
Existing solutions (epoxy, grease, In, Solder) Not Doing the Job!

TIM Must Haves :

- Lower Thermal Resistance (10 W/m•K typical. 5x reductions would be valuable)
- Easily Reworkable (Chips Fail)
- Allow Lateral Shear (chips get hot before the rest of the system)
- Long-Term Reliability and Consistency from Chip to Chip

Opportunities :

- *Nanotube/Nanowire materials may be able to meet this challenge*
- *Preliminary work in NSF, ONR, DARPA (MARCO), etc is promising*

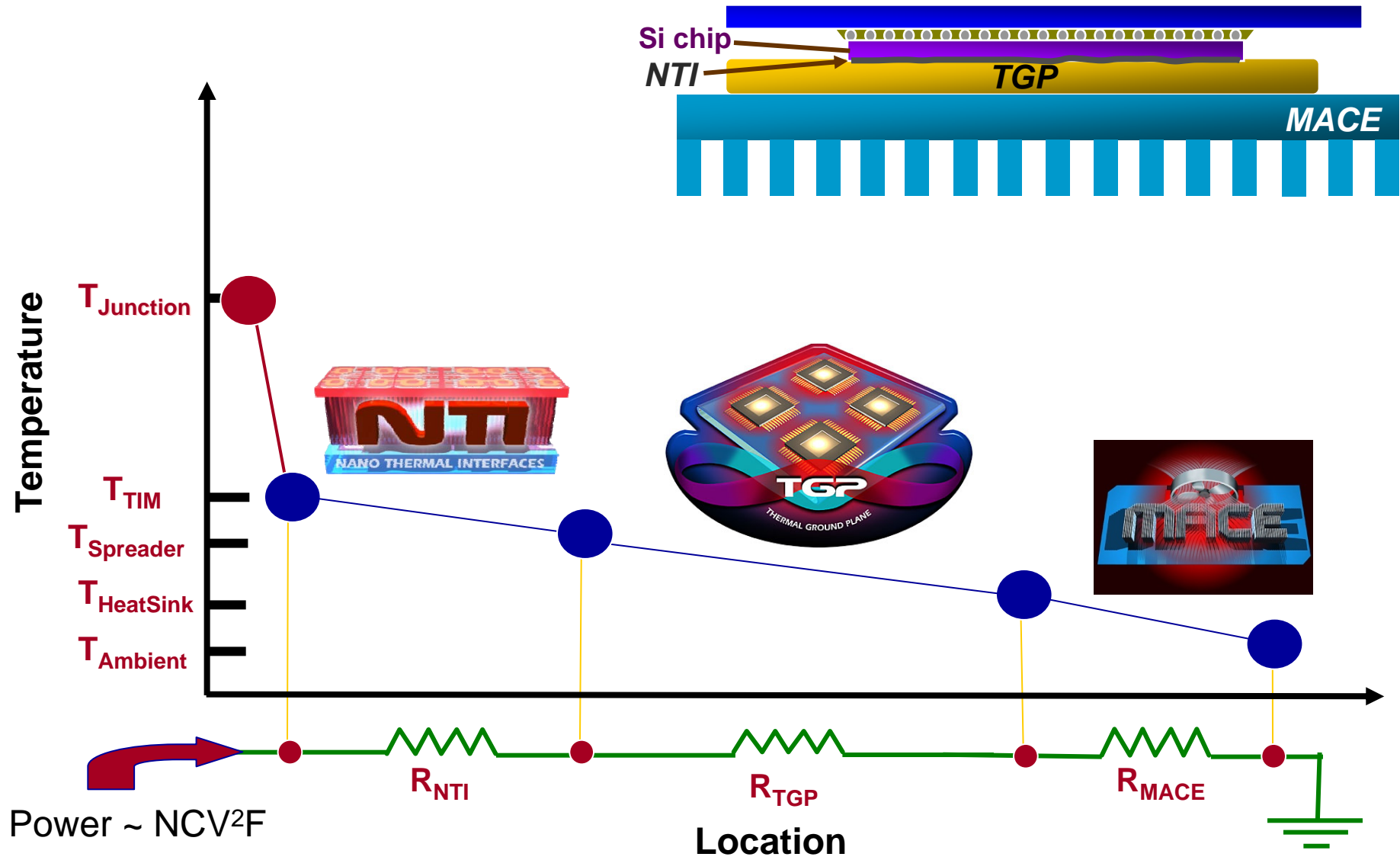


Program Kickoff 4/09.

Approved For Public Release, Distribution Unlimited

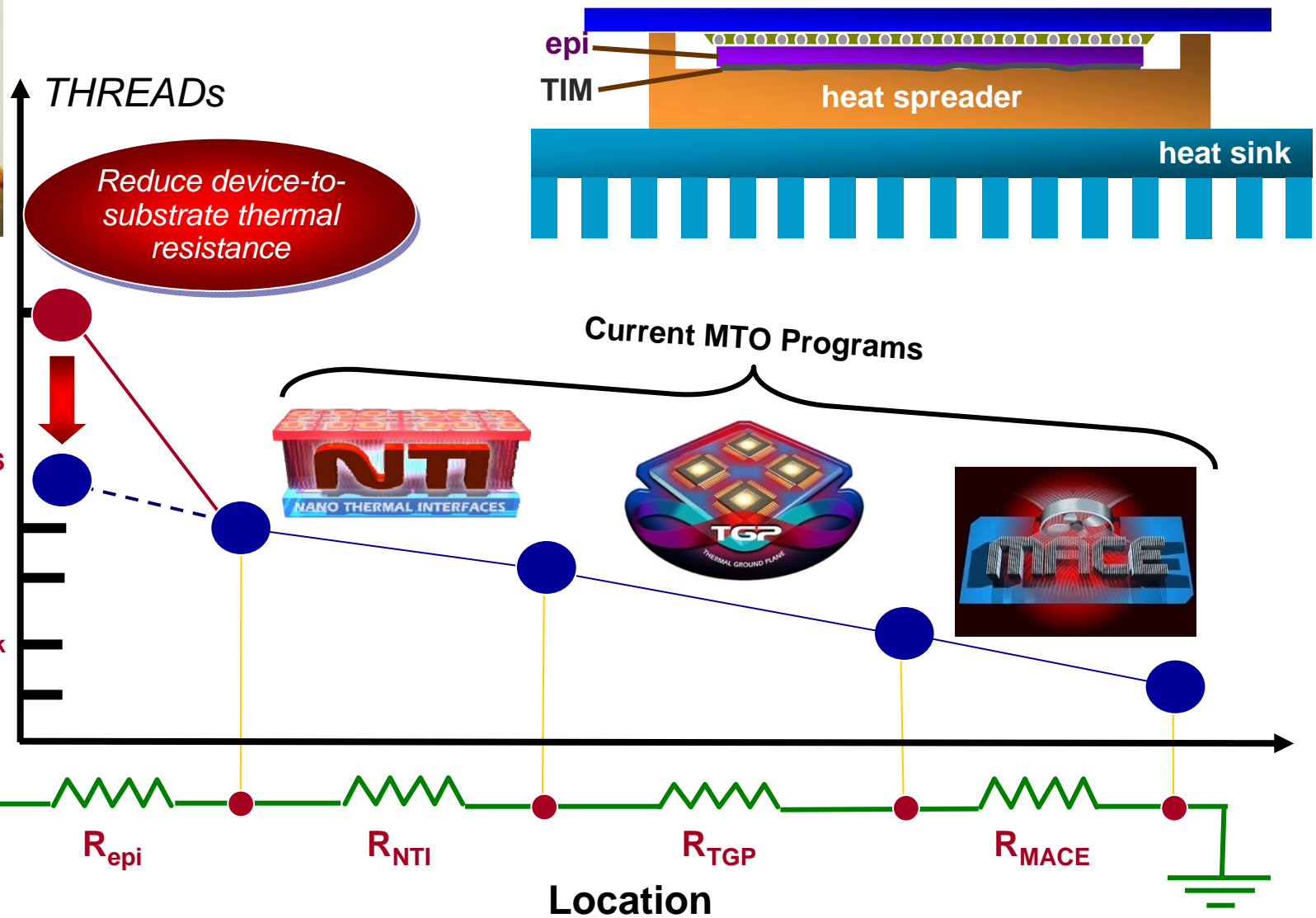


Thermal Management Portfolio





Technologies for Heat Removal from Electronics at the Device Scale (THREADS)





Technologies for Heat Removal from Electronics at the Device Scale (THREADS)



High Thermal Conductivity Over-layer for Heat Removal from Topside of Devices

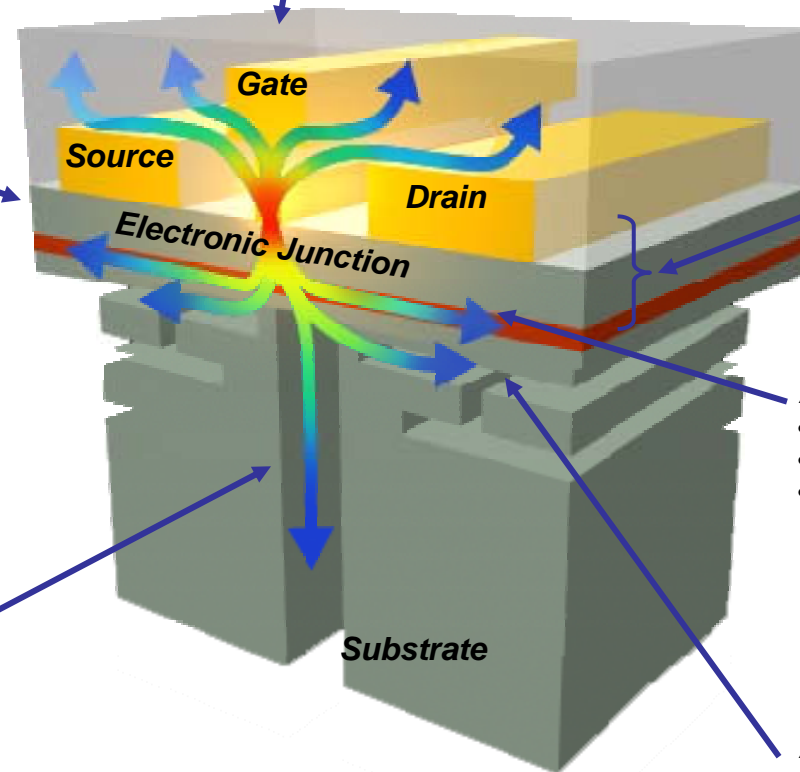
- High thermal conductivity in deposited material
- Conformal coverage with no gaps

High Thermal Conductivity Substrates

- Integrate lattice-mismatched heat spreaders
- Eliminate thermal interface resistance
- Match coefficient of thermal expansion of electronic material

Embedded Thermal Vias

- Micro-machined vias within ~1 micron of junction
- High thermal conductivity conformal fill materials
- Low coupling resistance for junction-to-thermal via, thermal via-to-heat sink



~ 1 μ m thickness

Anisotropic Heat Transport

- Efficient nanoscale phonon channel
- Long LO phonon lifetime (3ps)
- Extremely low electrical contact resistance

Active Liquid Cooling

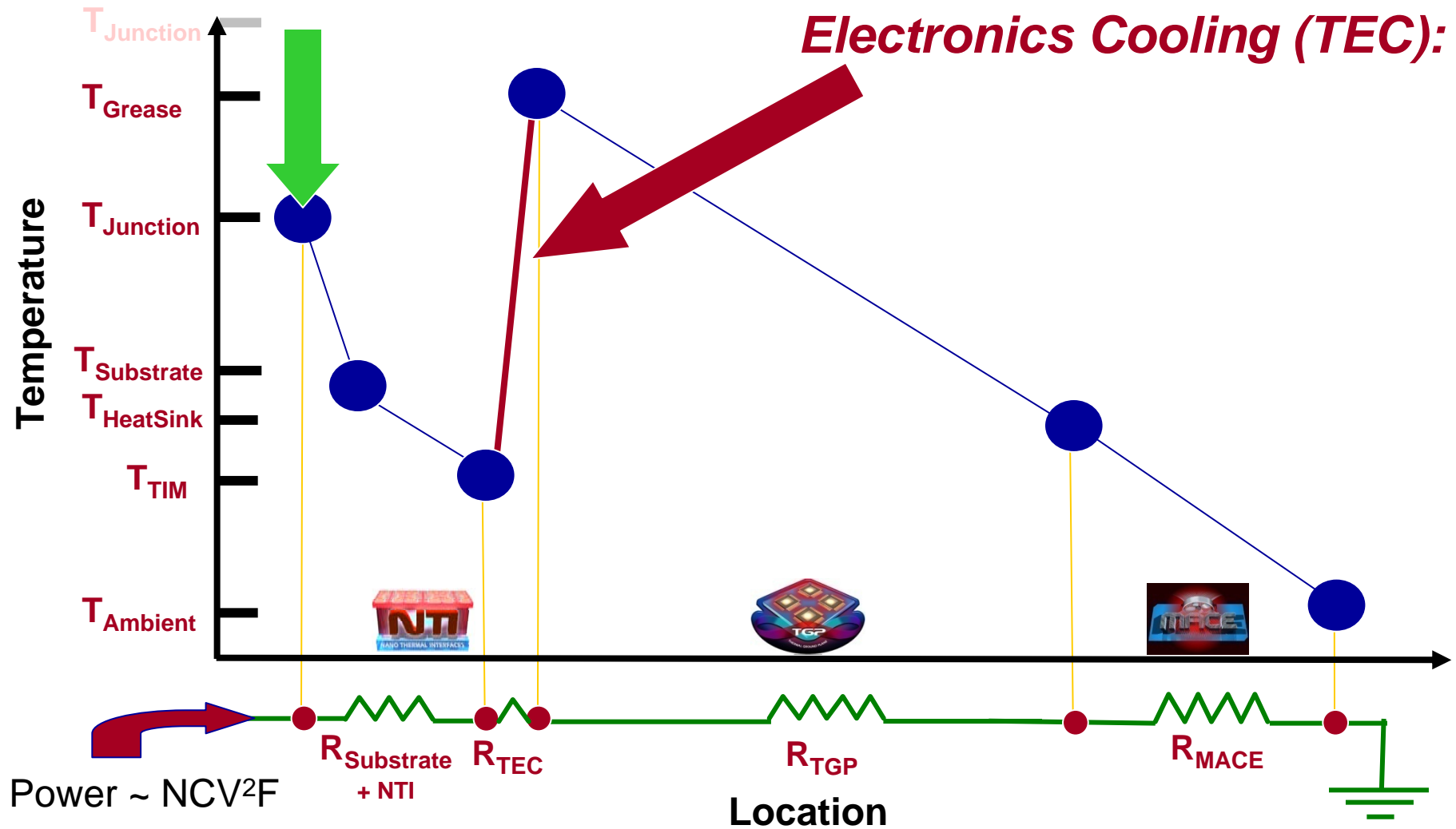
- Eliminate impact on device electrical properties due to time varying dielectric constant of liquid



Thermoelectrics for Electronics Cooling (TEC)



Thermoelectrics for Electronics Cooling (TEC):

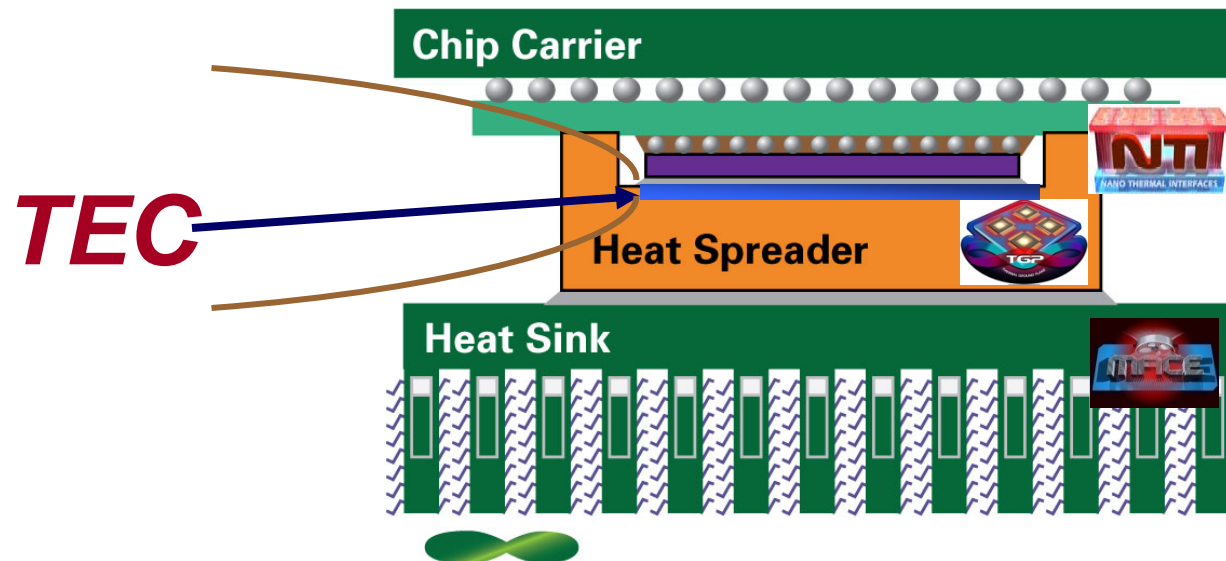




Thermoelectrics for Electronics Cooling (TEC)



TEC Vision : Enable greater power utilization margins in electronic materials while also increasing device reliability. Integrate TEC design with NTI, TGP, and MACE.



TEC Goals:

- Build complete modules with all interfaces that demonstrate TEC benefits
- Reduce ΔT of junction temperature for electronic devices
- Further increase electronic device power
- Increase device reliability
- Incorporate system with NTI, TGP, MACE designs for optimal thermal management system



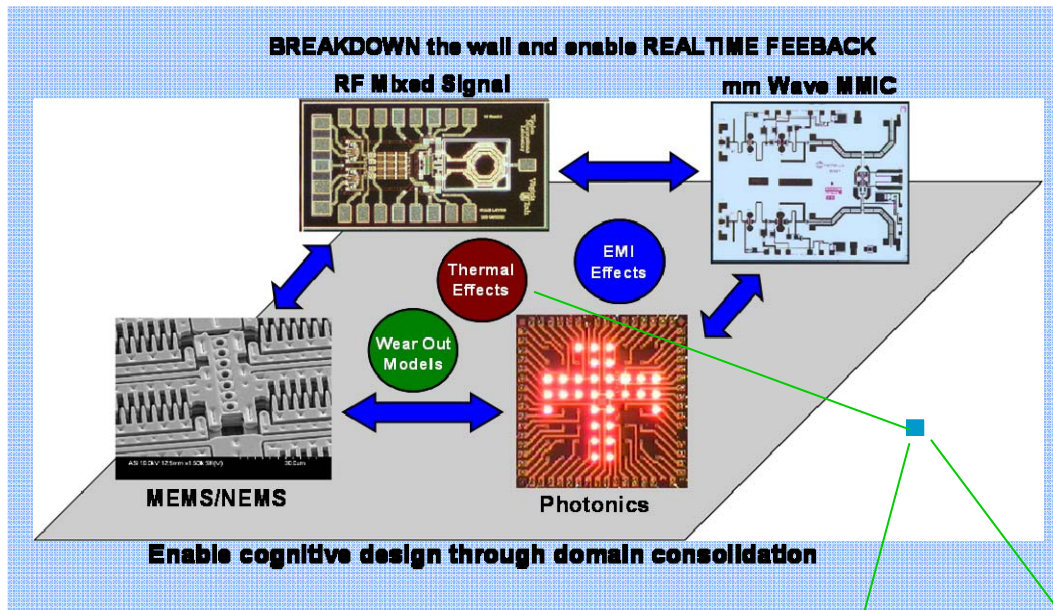
METACAD and DANTE Visions



- ➔ METACAD – Cognitive Design Support for Complex Systems
- ➔ DANTE – Integrated Thermal + Electrical IC Design Support



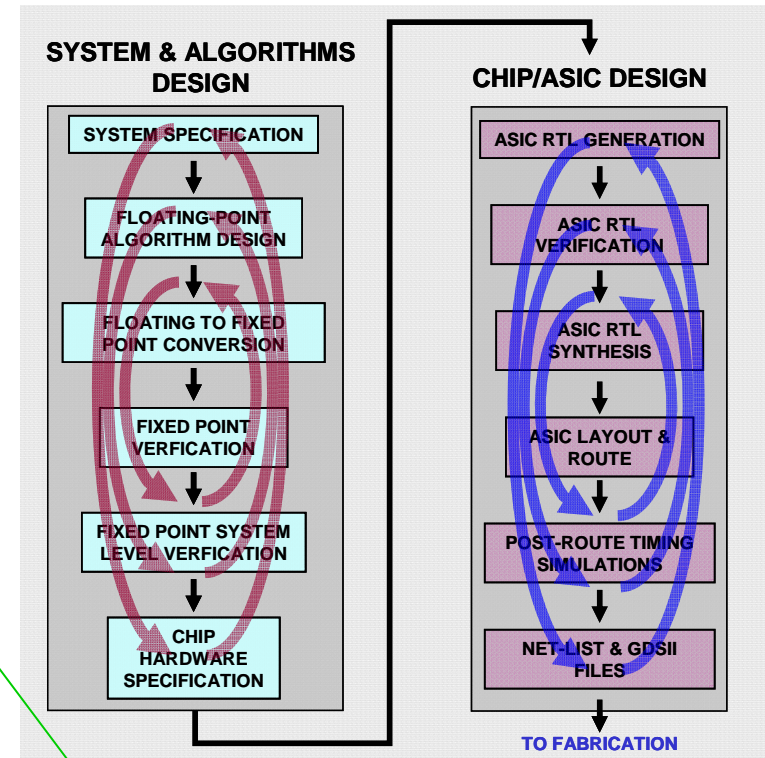
METACAD



Key Technologies

- NeoCAD/PAC/3DIC & Beyond
- Human/Machine Interaction Algorithms (Cognition)
- Models: Architecture, & Physical (Electrical, Thermal, Mechanical)

DANTE

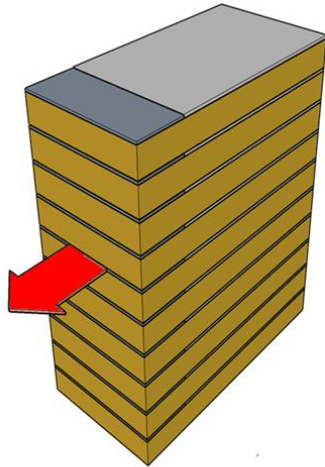


Key Technologies

- Models: Architecture & Thermal
- Multi-Physics Interactions included



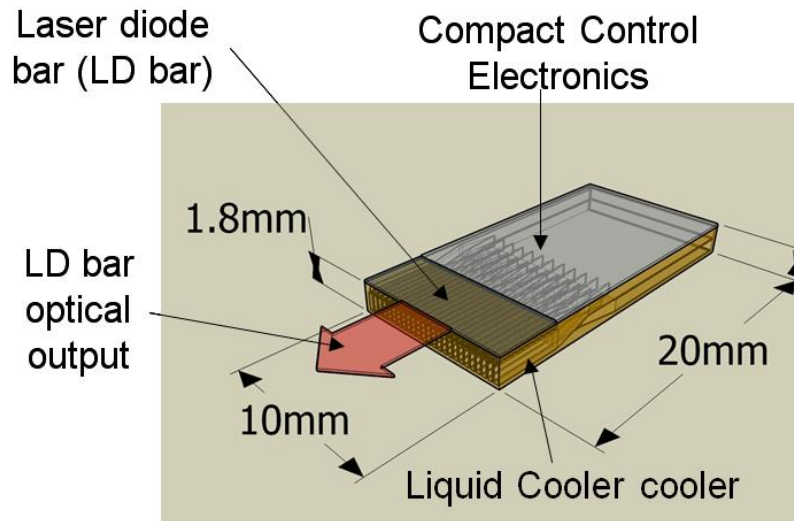
Direct Cooling of High Flux Laser Diode Elements



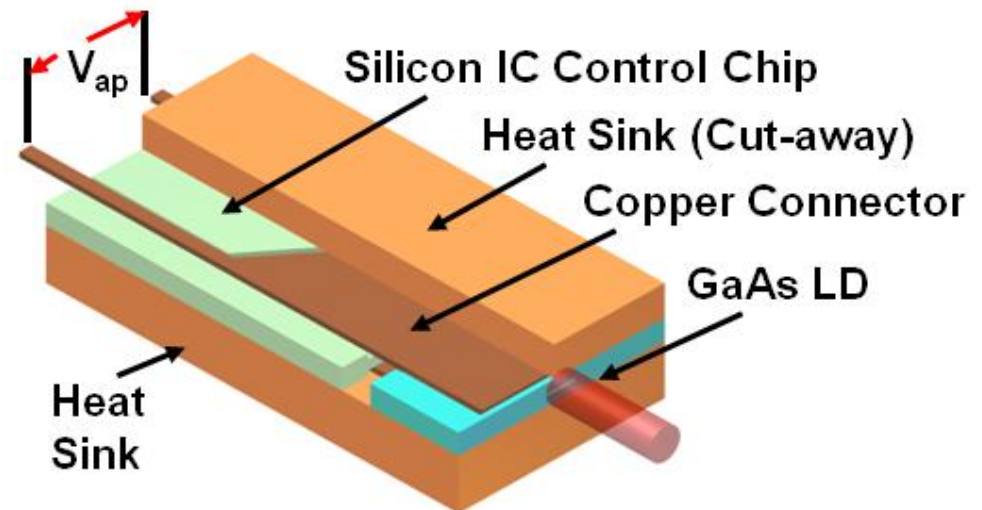
LDA Stack

Advantages include:

- **Laser diode protection at the single emitter level**
 - Intelligent protection is easier on a single emitter level
 - Enable control of current to each LD
 - Path to phased array LDAs and 3-4X higher power on target
- **35K lower facet temperature resulting in 10X longer life or**
- **5X improvement in performance resulting in ~1,000 Watts/cm-bar**



Single bar on 1.8 mm thick cooler





DARPA Organization



Agency Director
Deputy Director

\$3B/Year

\$???:Year

~80 other program managers

Mostly busy creating thermal management **problems** in the DoD

Tom Kenny
MTO Program Manager

Trying to solve some thermal management problems in the DoD



???

MICROSYSTEMS TECHNOLOGY OFFICE

MTO SYMPOSIUM



BUILDING THE FUTURE
FROM THE INSIDE OUT



Approved For Public Release, Distribution Unlimited